Search Notes			

Application/Co	ntrol No.	Applicant(s) Reexaminat	/Patent under ion
10/642,286		INUKAI ET	AL.
Examiner		Art Unit	
Marcus Charle	es	3682	

SEARCHED			
Class	Subclass	Date	Examiner
474	201, 260	6/14/2005	МС
	242-245	6/14/2005	мс
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